

Masked Dual-Rail Pre-Charge Logic

DPA-Resistance without Routing Constraints

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VLSI

Presentation Outline

- Introduction
- Problems of Current DPA-Resistant Logic Styles
- MDPL Cells and Circuits
- Experimental Results
- Conclusions and Future Work

Introduction

- Differential Power Analysis (DPA)
 - Implementation attack, side-channel attack
 - Used side channel: power consumption
 - Exploits data-dependency of a device's power consumption to get the secret key

Introduction

- DPA countermeasures overview
 - Protocol level
 - e.g. ephemeral keys
 - Algorithmic level
 - e.g. masked algorithms
 - Architectural level
 - e.g. noise engines, random delay cycles
 - Gate level
 - Dual-rail pre-charge (DRP) logic styles
 - Masking logic styles

Introduction

- DPA-resistant logic styles overview
 - Advantages
 - Hardware/software designers almost completely freed from considering DPA
 - “push-button” solution (semi-custom design)
 - Examples:
 - DRP: SABL, WDDL (C. Tiri et al.)
 - Masking: RSL (D. Suzuki et al.)

Masking CMOS Logic

Standard CMOS Logic				Masked CMOS Logic									
d_{t-1}	d_t	Energy Probability		Transitions of the value d of a node	Line no.	d_{t-1}	m_{t-1}	$d_{m_{t-1}}$	d_t	m_t	d_{m_t}	Energy Probability	
0	0	E_{00}	p_{00}		1	0	0	0	0	0	0	E_{00}	$\frac{1}{4}p_{00}$
0	1	E_{01}	p_{01}		2	0	0	0	1	1	0	E_{00}	$\frac{1}{4}p_{01}$
1	0	E_{10}	p_{10}		3	1	1	0	0	0	0	E_{00}	$\frac{1}{4}p_{10}$
1	1	E_{11}	p_{11}		4	1	1	0	1	1	0	E_{00}	$\frac{1}{4}p_{11}$
				5	0	0	0	0	1	1	E_{01}	$\frac{1}{4}p_{00}$	
				6	0	0	0	1	0	1	E_{01}	$\frac{1}{4}p_{01}$	
				7	1	1	0	0	1	1	E_{01}	$\frac{1}{4}p_{10}$	
				8	1	1	0	1	0	1	E_{01}	$\frac{1}{4}p_{11}$	
				9	0	1	1	0	0	0	E_{10}	$\frac{1}{4}p_{00}$	
				10	0	1	1	1	1	0	E_{10}	$\frac{1}{4}p_{01}$	
				11	1	0	1	0	0	0	E_{10}	$\frac{1}{4}p_{10}$	
				12	1	0	1	1	1	0	E_{10}	$\frac{1}{4}p_{11}$	
				13	0	1	1	0	1	1	E_{11}	$\frac{1}{4}p_{00}$	
				14	0	1	1	1	0	1	E_{11}	$\frac{1}{4}p_{01}$	
				15	1	0	1	0	1	1	E_{11}	$\frac{1}{4}p_{10}$	
				16	1	0	1	1	0	1	E_{11}	$\frac{1}{4}p_{11}$	

$$\begin{aligned}
 \mathcal{E}(DM_{d_t}) &= \mathcal{E}(M_{d_t=1}) - \mathcal{E}(M_{d_t=0}) \\
 &= \frac{p_{11}E_{11} + p_{01}E_{01}}{p_{11} + p_{01}} - \frac{p_{00}E_{00} + p_{10}E_{10}}{p_{00} + p_{10}} \\
 &\neq 0
 \end{aligned}$$

DPA attack

$$\mathcal{E}(M_{d_t=0}) = \mathcal{E}(M_{d_t=1}) = \frac{1}{4} (E_{00} + E_{01} + E_{10} + E_{11})$$

$$\mathcal{E}(DM_{d_t}) = 0$$

CMOS Logic:

$$E_{00} \approx E_{11} \ll E_{10} \neq E_{01}$$

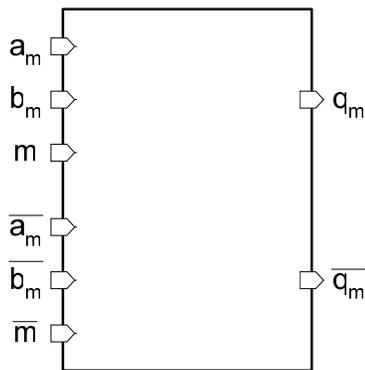
- Usability in semi-custom design flows
 - Design and characterization of new standard cells required
 - Tough constraints, e.g.
 - balancing of complementary wires (DRP)
 - careful timing of enable signal chains (RSL)
- Masking: glitches in masked CMOS circuits reduce its DPA resistance
 - RSA 2005: Mangard, Popp, Gammel

Masked Dual-Rail Pre-Charge Logic

- MDPL
 - Masked: for DPA resistance
 - one mask m for all signals: $d = d_m \oplus m$
 - Dual-rail pre-charged: to avoid glitches
 - Based on common standard cells
 - No tough constraints
 - no balanced wiring required
 - Suitable for semi-custom design

MDPL Combinational Cells

MDPL AND



$$q_m = ((a_m \oplus m) \wedge (b_m \oplus m)) \oplus m$$

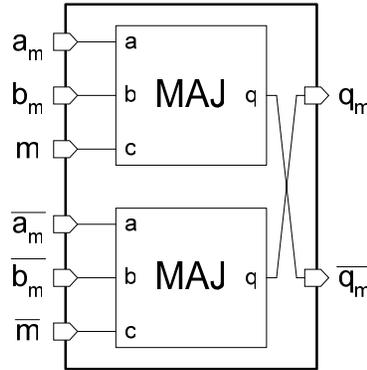
$$\overline{q_m} = ((\overline{a_m} \oplus \overline{m}) \wedge (\overline{b_m} \oplus \overline{m})) \oplus \overline{m}$$

Line no.	a_m	b_m	m	q_m	$\overline{a_m}$	$\overline{b_m}$	\overline{m}	$\overline{q_m}$
1	0	0	0	0	1	1	1	1
2	0	0	1	0	1	1	0	1
3	0	1	0	0	1	0	1	1
4	0	1	1	1	1	0	0	0
5	1	0	0	0	0	1	1	1
6	1	0	1	1	0	1	0	0
7	1	1	0	1	0	0	1	0
8	1	1	1	1	0	0	0	0

- pre-charge wave propagates correctly
- no glitches: monotonic transitions, MAJ is a monotonic increasing (positive) function

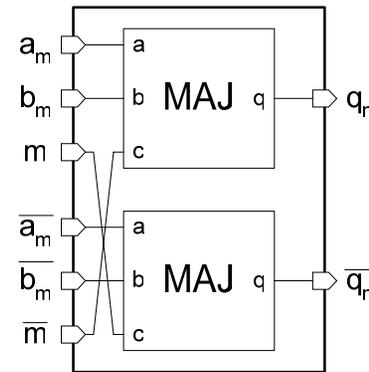
MDPL Combinational Cells

- MDPL NAND



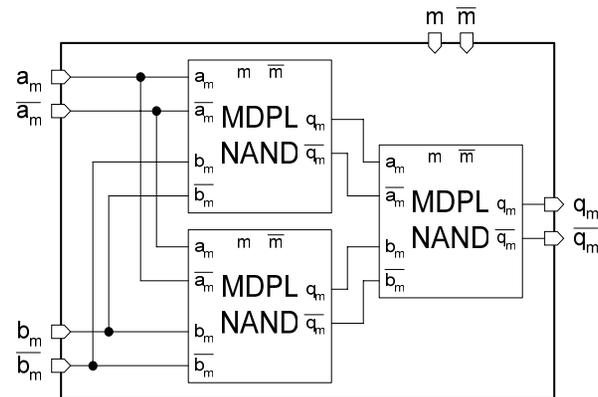
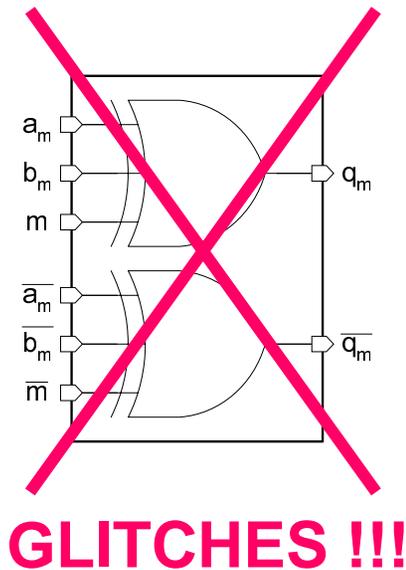
- MDPL OR (MDPL NOR)

Line no.	a_m	b_m	m	q_m	$\overline{a_m}$	$\overline{b_m}$	\overline{m}	$\overline{q_m}$
1	0	0	0	0	1	1	1	1
2	0	0	1	0	1	1	0	1
3	0	1	0	1	1	0	1	0
4	0	1	1	0	1	0	0	1
5	1	0	0	1	0	1	1	0
6	1	0	1	0	0	1	0	1
7	1	1	0	1	0	0	1	0
8	1	1	1	1	0	0	0	0



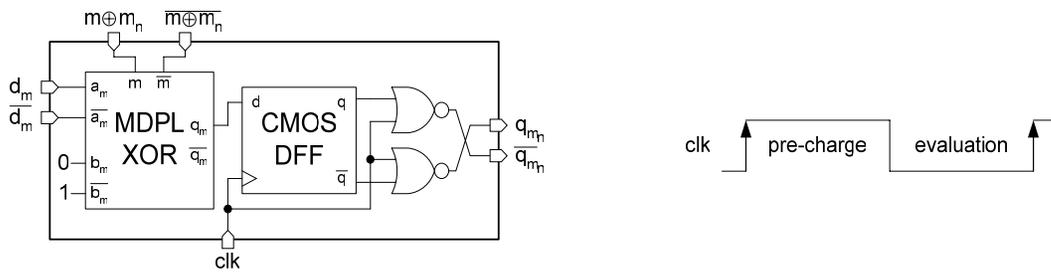
MDPL Combinational Cells

MDPL XOR (MDPL XNOR)

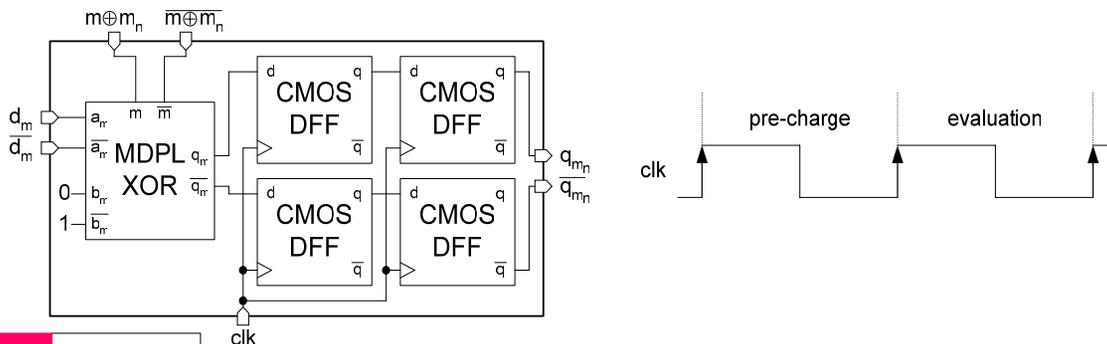


MDPL Sequential Cells

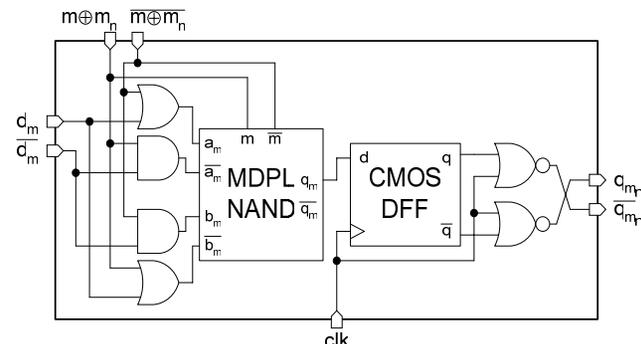
- MDPL DFF
 - performs mask switching (m, m_n)
 - starts pre-charge wave



MDPL DFF that stores the pre-charge wave:



MDPL DFF with optimized MDPL XOR:



MDPL Cells Implementations

- Possibilities
 - **Out of common standard cells**
 - **cheap**
 - but not optimal:
 - time-of-evaluation of MAJ gate
 - not all internal nodes of the MAJ gate are pre-charged
 - New “CMOS” standard cells
 - New “DRP” standard cells
 - mask considered in differential pull-down network

MDPL Cells Summary

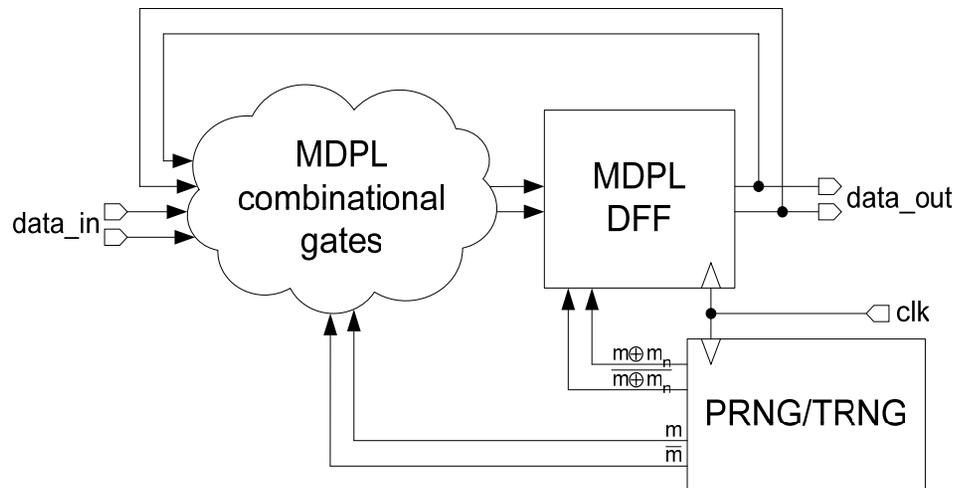
- MDPL cells and their CMOS implementations (austriamicrosystems C35B3 standard cell library)

MDPL cell	CMOS implementation of MDPL cell	Area (gate equivalents) of		Ratio $\frac{MDPL}{CMOS}$
		MDPL cell	std. CMOS cell	
Inverter	Wire swapping	0	0.67	0
Buffer	2×Buffer	2	1	2
AND, OR (2-in)	2×MAJ (3-in)	4	1.67	2.4
NAND, NOR (2-in)	2×MAJ (3-in)	4	1	4
XOR (2-in)	6×MAJ (3-in)	12	2.33	5.1
XNOR (2-in)	6×MAJ (3-in)	12	2	6
D-Flip-Flop	2×AND, 2×OR (both 2-in) 2×MAJ (3-in), 1×D-FF	17.67	5	3.5

- Indicates 4 to 5 times area increase

MDPL Circuits

- General architecture
 - 1 mask for the whole circuit, changed every clock cycle
 - SPA on mask nets not possible

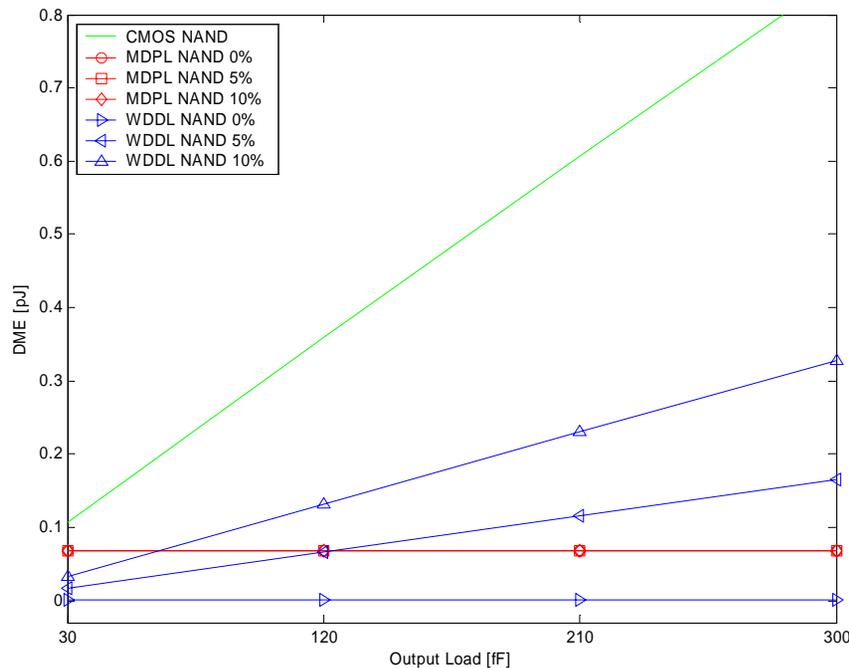


MDPL Circuits

- MDPL semi-custom design
 - HDL high-level design
 - Synthesis
 - restrict available standard cells
 - Logic style conversion
 - cell output load OK?
 - replace CMOS cells by corresponding MDPL cells
 - removal of inverters
 - insertion of CMOS \leftrightarrow MDPL interface circuitry
 - CTG
 - set clock-tree leaf pins within MDPL DFFs
 - Place
 - Route

Experimental Results

- Comparison of DPA-resistance of CMOS, WDDL and MDPL NAND gates concerning unbalanced complementary wires



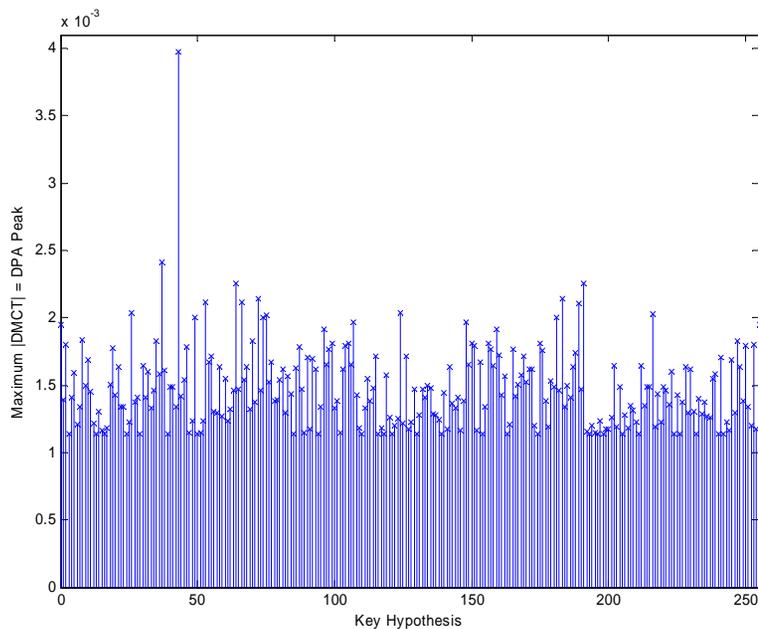
Experimental Results

- Comparison of an AES module implemented in CMOS and in MDPL
 - Area
 - 4.54x higher for MDPL
 - Speed
 - 0.58x of CMOS
 - Power
 - 4x – 6x higher for MDPL

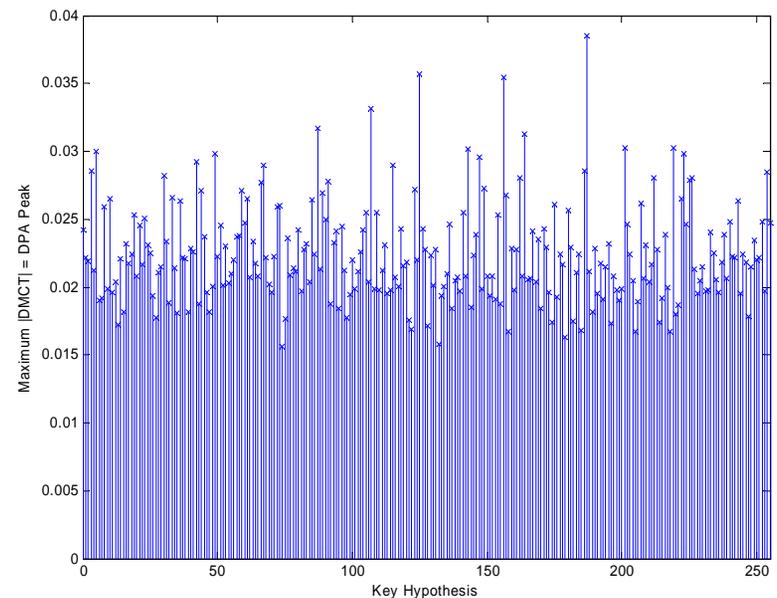
Experimental Results

- DPA-resistance (simulated power traces)
 - output of first SubBytes operation was targeted
 - 256 encryptions

AES implemented in CMOS:



AES implemented in MDPL:



Conclusions and Future Work

- MDPL is suitable for semi-custom design
 - Only commonly available standard cells are necessary
 - No balancing wires constraint – is usually the biggest problem of many DPA-resistant logic styles
- Experimental results are OK
 - Practical results expected from SCARD project
 - <http://www.scard-project.org>
- Trade-off is in increased area and power and reduced speed

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